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INTEGRATED CIRCUIT MEMORY SYSTEMS HAVING PROGRAMMABLE SIGNAL BUFFERS FOR ADJUSTING SIGNAL TRANSMISSION DELAYS AND METHODS OF OPERATING SAME

CROSS REFERENCE TO RELATED APPLICATION

This application claims the benefit of Korean Application No. 2000-50164, filed August 28, 2000, the disclosure of which is hereby incorporated herein by reference.

BACKGROUND OF THE INVENTION

The present invention relates generally to the field of integrated circuit devices, and, more particularly, to signal distribution circuitry used in integrated circuit devices.

Signal transmission times between respective memory devices in a memory system may differ based on the positions of the memory devices. The signal transmission times between signals following similar length paths may also differ due to skew between the signals. Differences in signal transmission times and/or skew may reduce a valid data window for determining a maximum operating frequency and may increase setup times and hold times for signals.

To compensate for skew, conventional memory devices and controllers may include a phase locked loop (PLL) or a delay locked loop (DLL). Unfortunately, this may increase the size of the memory device. Also, designing the PLL or DLL may cause difficulties in developing the memory device.

FIG. 1 is a schematic of a conventional memory system that illustrates different signal delays between modules and/or memory devices. FIG. 2 is a timing diagram that illustrates skew between signals and the reduction of a valid data window due to the skew.

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Referring now to FIG. 1, a conventional memory system comprises a plurality of memory modules 11, 13, and 15 controlled by a memory controller 10. The transmission time of a signal between a memory module 11, 13, or 15 and the memory controller 10 varies according to the position of the memory module 11, 13, or 15. For example, the transmission time of a signal between the memory module 11 and the memory controller 10 is t0 and the transmission time between the memory module 15 and the memory controller 10 is t10.

Memory module 11 comprises a plurality of memory devices 21, 23, 25, and 27. The transmission time of a signal between the memory controller 10 and one of the memory devices 21, 23, 25, or 27 varies according to the position of the memory device 21, 23, 25, or 27. For example, the transmission time of a signal between the memory device 21 and the memory controller 10 is t1 and the transmission time between the memory device 27 and the memory controller 10 is t4.

Thus, the transmission time of a signal between the memory controller 10 and a memory module 11, 13, or 15 varies according to the position of the memory module. Furthermore, the transmission time of a signal between the memory controller and a memory device 21, 23, 25, or 27 varies according to the position of the memory device. Similar principles apply to memory module 13, which comprises memory devices 31, 33, 35, and 37, and memory module 15, which comprises memory devices 51, 53, 55, and 57.

Referring now to FIG. 2, time t1 illustrates a data setup time that is increased due to skew between signals and/or differences in signal transmission time between the memory controller 10 and the memory modules 11, 13, and 15 and/or the memory devices contained therein. Time t3 illustrates a data hold time that is increased due to skew between signals and/or differences in signal transmission time between the memory controller 10 and the memory modules 11, 13, and 15 and/or the memory devices contained therein. Time t2 denotes a valid data window reduced by the times t1 and t3.

In a conventional memory system, various integrated circuit memory devices, such as memory devices 21, 31, and 51, may be connected to each other and there may be differences in transmission time for signals between the memory controller 10 and the memory devices 21, 31, and 51 based on the position of the memory device 21, 31, and 51. In addition, skew may exist between signals. The differences in signal transmission time and/or skew may increase the data setup time and/or the data

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hold time, and may reduce the valid data window for determining the maximum operating frequency of the memory system.

To compensate for skew and/or the differences in signal transmission time, a memory device and/or a memory controller may use a PLL and/or a DLL.

Unfortunately, incorporating a PLL and/or a DLL into memory systems may increase the size of the memory systems. Also, designing a PLL and/or DLL may increase the development complexity of memory systems.

SUMMARY OF THE INVENTION

Embodiments of the present invention provide integrated circuit memory systems, memory controllers, memory devices, and methods of operating same. For example, in some embodiments, an integrated circuit memory system comprises one or more memory modules in which at least one of the memory modules is responsive to a control signal and has delay control information stored thereon. The memory system further comprises a memory controller that is configured to generate the control signal in response to the delay control information.

In further embodiments, the memory controller comprises a delay control register that is configured to receive and to store the delay control information therein and an output buffer that is configured to generate the control signal in response to an input control signal and the delay control information stored in the delay control register.

In still further embodiments, the memory controller comprises an input buffer that is configured to receive data from one or more of the memory modules at an input thereof and to provide the received data at an output thereof in response to the delay control information stored in the delay control register.

In other embodiments, the control signal comprises a command control signal, an address control signal, and data, and the output buffer comprises a command output buffer that is configured to generate the command control signal in response to an input command control signal and the delay control information stored in the delay control register, an address output buffer that is configured to generate the address control signal in response to an input address control signal and the delay information stored in the delay control register, and a data output buffer that is configured to generate the data in response to input data and the delay information stored in the delay control register.

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In still other embodiments, at least one of the memory modules comprises a plurality of memory devices. Moreover, at least one of the memory devices comprises a delay control register that is configured to receive at least some of the delay control information and to store that information therein, an input buffer that is configured to generate a second control signal in response to the control signal output from the controller and the delay control information stored in the delay control register, and a memory cell array that is responsive to the second control signal.

Thus, in accordance with embodiments of the present invention, differences in signal transmission times between a memory controller and memory devices may be reduced by delaying signals at the memory controller and/or the memory devices. The operating frequency of a memory system may be improved by reducing signal skew between signals destined for different memory devices in the memory system.

BRIEF DESCRIPTION OF THE DRAWINGS

Other features of the present invention will be more readily understood from the following detailed description of specific embodiments thereof when read in conjunction with the accompanying drawings, in which:

- FIG. 1 is a schematic that illustrates a conventional memory system;
- FIG. 2 is a timing diagram that illustrates skew between signals generated in the memory system of FIG. 1;
- FIG. 3 is a block diagram that illustrates memory systems in accordance with embodiments of the present invention;
- **FIG. 4** illustrates memory controllers in accordance with embodiments of the present invention;
- FIG. 5 illustrates memory devices in accordance with embodiments of the present invention; and
- FIG. 6A is a timing diagram that illustrates the valid data window of a conventional memory system; and
- FIG. 6B is a timing diagram that illustrates the valid data window of memory systems in accordance with embodiments of the present invention.

DETAILED DESCRIPTION OF PREFERRED EMBODIMENTS

While the invention is susceptible to various modifications and alternative forms, specific embodiments thereof are shown by way of example in the drawings

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and will herein be described in detail. It should be understood, however, that there is no intent to limit the invention to the particular forms disclosed, but on the contrary, the invention is to cover all modifications, equivalents, and alternatives falling within the spirit and scope of the invention as defined by the claims. Like reference numbers signify like elements throughout the description of the figures. It will also be understood that when an element is referred to as being "connected" or "coupled" to another element, it can be directly connected or coupled to the other element or intervening elements may also be present. In contrast, when an element is referred to as being "directly connected" or "directly coupled" to another element, there are no intervening elements present.

FIG. 3 illustrates a memory system, in accordance with embodiments of the present invention, that comprises a controller 100 and a plurality of memory modules 110, 130, and 150. Memory module 110 comprises a plurality of memory devices 111, 113, 115, and 117. Memory module 130 comprises a plurality of memory devices 131, 133, 135, and 137. Memory module 150 comprises a plurality of memory devices 151, 153, 155, and 157. The memory modules 110, 130, and 150 further comprise serial presence detectors (SPDs), 220A, 220B, and 220C, respectively.

SPD1 220A stores information on the positions of the memory devices 111, 113, 115, and 117 in the memory module 110. The SPD1 220A stores additional information, such as the respective wiring distances from the controller 100 to the memory devices 111, 113, 115, and 117 and operating conditions that are associated with the wiring distance (e.g., operation voltages based on the length and the conductivity of a wiring material). This information may be recorded in the SPD1 220A during design of the memory interface. SPD2 220B and SPDn 220C store similar information for memory modules 130 and 150, respectively.

During initialization of the memory system, information on the respective memory modules 110, 130, and 150 is sent from the SPD1 220A, SPD2 220B, and/or SPDn 220C to the controller 100 through a serial bus. Therefore, the controller 100 may obtain the positions of the memory modules 110, 130, and 150 and the memory devices 111 through 157.

FIG. 4 illustrates the memory controller 100 in accordance with embodiments of the present invention. The memory controller 100 comprises a delay control register 400, an output buffer 410, and a module selector 430. The delay control

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register 400 receives delay control information DSP from SPD1 220A, SPD2 220B, and/or SPDn 220C. The module selector 430 generates the module selection signals MODS1 and MODS2 for selecting a specific memory module 110, 130, or 150 in response to a clock signal CLK and a module address signal MOD.

The output buffer 410 comprises a delay controller 417, a command output buffer 411, an address output buffer 413, and a data output buffer 415. In other embodiments, the delay controller 417 may be viewed as a separate component from the output buffer 410. The output buffer 410 applies a delay to an internal command signal COMI, an internal address signal ADDI, and internal write data DATI to generate a command signal COM, an address signal ADD, and write data DAT, respectively, in response to the module selection signals MODS1 and MODS2. The delay that is applied by the output buffer 410 is based on the delay control information contained in the delay control register 400.

The delay controller 417 generates an output signal specifying a delay time in response to the delay control information contained in the delay control register 400 and the module selection signal MODS2. The command output buffer 411 delays the internal command signal COMI in response to the output signal of the delay controller 417 and the module selection signal MODS1. The address output buffer 413 delays the internal address signal ADDI in response to the output signal of the delay controller 417 and the module selection signal MODS1. The data output buffer 415 delays the write data DATI in response to the output signal of the delay controller 417 and the module selection signal MODS1.

The memory controller 100 further comprises an input buffer 420. The input buffer 420 comprises a delay controller 421 and a data input buffer 423. In other embodiments, the delay controller 421 may be viewed as a separate component from the input buffer 420. The delay controller 421 generates an output signal specifying a delay time in response to the delay control information contained in the delay control register 400 and an enable signal EN. The data input buffer 423 applies a delay to read data DAT, which are received from the memory devices 111 through 157, in response to the output signal of the delay controller 421. The input buffer 420 then provides the read data to other circuitry of the memory controller 100 after expiration of the delay time.

Referring again to FIG. 3, for purposes of illustration, it is assumed that the memory system comprises eight total memory modules, with memory modules 110,

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130, and 150 representing the first, second, and eighth modules, respectively. It will be understood, however, that memory systems may contain more or fewer memory modules in accordance with other embodiments of the present invention. During initialization of the memory system, the delay control register 400 reads the information contained in the SPDs 220A, 220B, and 220C and may associate respective transmission delay values with the memory modules 110, 130, through 150, and may also associate respective transmission delay values with the memory devices 111 through 157 contained in the memory modules 110, 130 through 150, based on the characteristics of a signal received with respect to the memory modules 110, 130, through 150 and the memory devices 111 through 157 by a basic input/output system (BIOS). In other words, a transmission delay value represents a duration of time that it takes a signal to travel from the memory controller 100 to a memory module and/or a memory device.

When writing data to one of the memory modules 110, 130, through 150, if the module address signal MOD corresponds to a memory module that has a transmission delay value associated therewith that is greater than or equal to the transmission delay values associated with the other memory modules, then the module selector 430 activates the module selection signal MODS1 and deactivates the module selection signal MODS2 in response to the clock signal CLK. Because the module selection signal MODS2 is deactivated, the delay controller 417 is disabled. Therefore, the internal command signal COMI, the internal address signal ADDI, and the write data **DATI** may be output as the command signal **COM**, the address signal ADD, and data DAT without any delay based on the delay control information stored in the delay control register 400 being applied thereto by the output buffer 410. In the example shown in FIG. 3, memory module 150 may correspond to the memory module that has the greatest transmission delay value associated therewith as it is located the farthest from the memory controller 100. Likewise, memory device 157 may correspond to a memory device that has the greatest transmission delay value associated therewith as it is located the farthest from the memory controller 100. It will be understood, however, that in other embodiments of the present invention, the memory module and/or the memory device with the greatest transmission delay value associated therewith may not necessarily be located the farthest distance away from the memory controller.

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If, however, the module address signal MOD corresponds to a memory module that has a transmission delay value associated therewith that is less than one or more transmission delay values associated with other memory modules, then the module selector 430 deactivates the module selection signal MODS1 and activates the module selection signal MODS2 in response to the clock signal. In the example of FIG. 3, if the module address signal MOD corresponds to any memory module other than memory module 150, then the module selection signal MODS1 is deactivated and the module selection signal MODS2 is activated.

The delay controller 417 generates an output signal specifying a delay time in response to the delay control information contained in the delay control register 400 and the module selection signal MODS2. The delay time is a value, which is determined based on previously obtained SPD information, for reducing skew between signals transmitted between the memory controller and the memory modules 110, 130, and 150, and for reducing differences in signal delays for signals transmitted between the memory controller and the memory modules 110, 130, and 150. The delay time is applied to signals received at the command output buffer 411, the address output buffer 413, and the data output buffer 415. Therefore, the command signal COM, the address signal ADD, and the write data DAT are generated by delaying the internal command signal COMI, the internal address signal ADDI, and the write data DATI, respectively, by the delay time specified by the output signal of the delay controller 417.

When reading data from one of the memory modules 110, 130, through 150, if data is being read from a memory device contained in a memory module that has a transmission delay value associated therewith that is greater than or equal to the transmission delay values associated with the other memory modules (e.g., memory device 157 of memory module 150 as discussed above), then the input buffer 420 may provide read data to other circuitry of the memory controller 100 without any delay based on the delay control information stored in the delay control register 400 being applied thereto by the data input buffer 423. If, however, data is being read from a memory device contained in a memory module that has a transmission delay value that is less than one or more transmission delay values associated with other memory modules (e.g., memory devices 111 through 137 of memory modules 110 and 130 as discussed above), then the delay controller 421 generates an output signal specifying a delay time in response to the delay control information contained in the delay control

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register 400 and the enable signal EN. The data input buffer 423 applies the delay time to read data DAT, which are received from the memory devices 111 through 157, in response to the output signal of the delay controller 421. The input buffer 420 then provides the read data to other circuitry of the memory controller 100 after expiration of the delay time.

FIG. 4 illustrates methods of operating memory systems, memory controllers, and memory modules in accordance with embodiments of the present invention. Memory systems operate by controlling the delay that is applied to signals output from the memory controller 100 and destined for the memory modules 110, 130, through 150, and by controlling the delay that is applied to data received from the memory modules 110, 130, through 150 at the memory controller 100.

Delay control information DSP is received from the SPD1 220A, SPD2 220B, and/or SPDn 220C and is stored in the delay control register 400. The module selector 430 activates a module selection signal MODS1 or MODS2 for selecting one of the memory modules 110, 130, and 150 in response to the clock signal CLK. The delay controllers 417 and 421 generate respective output signals specifying a delay time in response to the delay control information contained in the delay control register 400. The module selector 430 activates the module selection signal MODS1 and deactivates the module selection signal MODS2 if the memory module to be written to has a transmission delay value associated therewith that is greater than or equal to the transmission delay values associated with the other memory modules. Conversely, the module selector 430 activates the module selection signal MODS2 and deactivates the module selection signal MODS1 if the memory module to be written to has a transmission delay value associated therewith that is less than one or more transmission delay values associated with other memory modules. The module selection signals MODS1 and MODS2 control whether the output buffer 410 applies a delay time received from the delay controller 417 to the internal command signal COMI, the internal address signal ADDI, and the write data DATI, to generate the command signal COM, the address signal ADD, and the write data DAT.

If data is being read from a memory device contained in a memory module that has a transmission delay value associated therewith that is greater than or equal to the transmission delay values associated with the other memory modules (e.g., memory device 157 of memory module 150 as discussed above), then the input buffer 420 may provide read data to other circuitry of the memory controller 100 without

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any delay based on the delay control information stored in the delay control register 400 being applied thereto by the data input buffer 423. If, however, data is being read from a memory device contained in a memory module that has a transmission delay value that is less than one or more transmission delay values associated with other memory modules (e.g., memory devices 111 through 137 of memory modules 110 and 130 as discussed above), then the delay controller 421 generates an output signal specifying a delay time in response to the delay control information contained in the delay control register 400 and the enable signal EN. The data input buffer 423 applies the delay time to read data DAT, which are received from the memory devices 111 through 157, in response to the output signal of the delay controller 421. The input buffer 420 then provides the read data to other circuitry of the memory controller 100 after expiration of the delay time.

FIG. 5 illustrates the memory device 111 in more detail, in accordance with embodiments of the present invention. The other memory devices 113 through 157 may be configured similarly to memory device 111, in accordance with embodiments of the present invention. Memory device 111 comprises a delay control register 500, an input buffer 510, and a memory cell array 520. The delay control register 500 receives delay control information DS from the memory controller 100 and stores the received delay control information DS. The delay control register 500 receives the delay control information DS and sets a delay time for the memory device 111, which is based on respective delay times for other memory devices 113 through 157, during initialization of the memory system.

ADD, and write data DAT from the memory controller 100, which have been generated by applying a delay to the internal command signal COMI, the internal address signal ADDI, and the write data DATI, respectively. Note that for a memory device that has the greatest transmission delay value associated therewith (e.g., memory device 157), the command signal COM, the address signal ADD, and the write data DAT correspond to the internal command signal COMI, the internal address signal ADDI, and the write data DATI. The input buffer 510 applies a delay to the received command signal COM, the address signal ADD, and the write data DAT. The delay time applied by the input buffer 510 is based on the delay control information for the device 111, which is stored in the delay control register 500.

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The input buffer 510 comprises a command input buffer 511, an address input buffer 513, a data input buffer 515, and a delay controller 517. In other embodiments, the delay controller 517 may be viewed as a separate component from the input buffer 510. The delay controller 517 generates an output signal specifying a delay time in response to the delay control information contained in the delay control register 500 and an enable signal EN.

The data input buffer 515 delays the write data **DAT** by the delay time and buffers the delayed write data **DAT** in response to the output signal of the delay controller 517. The address input buffer 513 delays the address signal **ADD** by the delay time and buffers the delayed address signal **ADD** in response to the output signal of the delay controller 517. The command input buffer 511 delays the command signal **COM** by the delay time and buffers the delayed command signal **COM** in response to the output signal of the delay controller 517.

In general, in a memory device that has the greatest transmission delay associated there with, the input buffer 510 does not apply any additional delay to incoming signals. For example, assuming memory device 157 has the greatest transmission delay value associated therewith, when data is written to the memory device 157, the input buffer for memory device 157 does not apply additional delay based on delay control information stored in a delay register. By contrast, when data is written to the memory device 111, which is close to the memory controller 100 and has a relatively short transmission delay time associated therewith, the input buffer 510 applies a relatively long delay to the received command signal COM, address signal ADD, and data DAT. When data is being read from one of the memory devices 111 through 157, any additional delay time applied to the read data is controlled by the memory controller 100 as discussed hereinabove.

FIG. 5 illustrates methods of operating memory devices in accordance with embodiments of the present invention. Referring to FIG. 5, the delay control information DS is received from the memory controller 100 in the delay register 500. The delay controller 517 generates an output signal specifying a delay time in response to the delay control information contained in the delay control register 500 and an enable signal EN. The input buffer 510 delays an input signal received from, for example, a memory controller by the delay time. The input signal may comprise a command signal, an address signal, and write data.

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Therefore, in accordance with embodiments of the present invention, differences in signal transmission times between a memory controller and memory devices may be reduced by delaying signals at the memory controller and/or the memory devices. The operating frequency of a memory system may be improved by reducing signal skew between signals destined for different memory devices in the memory system.

FIGS. 6A and 6B are timing diagrams that illustrate the valid data window of a conventional memory system and the valid data window of a memory system in accordance with embodiments of the present invention, respectively. FIG. 6A shows skew in a conventional memory system that is generated due to differences in the arrival time of signals. Accordingly, the skew may reduce the valid data window time period. Time t1 illustrates a data setup time that is increased due to skew between signals and/or differences in signal transmission time. Time t3 illustrates a data hold time that is increased due to skew between signals and/or differences in signal transmission time. Time t2 denotes a valid data window reduced by the times t1 and t3.

FIG. 6B shows the valid data window according to embodiments of the present invention. Time t1' illustrates a data setup time that is increased due to skew between signals and/or differences in signal transmission time. Time t3' illustrates a data hold time that is increased due to skew between signals and/or differences in signal transmission time. Time t2' denotes a valid data window reduced by the times t1' and t3'.

Because times t1' and t3' are less than times t1 and t3 of FIG. 6A, respectively, the valid data window time period may be shorter than that provided by conventional memory systems. Accordingly, memory systems, in accordance with embodiments of the present invention, may operate at higher frequencies.

Many variations and modifications can be made to the preferred embodiments without substantially departing from the principles of the present invention. All such variations and modifications are intended to be included herein within the scope of the present invention, as set forth in the following claims.